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Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of informati Substitute for form 1449AVPTO Complete if Known INFORMATION DISCLOSURE 10/047461 **Application Number** STATEMENT BY APPLICANT January 14, 2002 **Filing Date** es necessary) **First Named Inventor** Guttman, Andras NOV 1 2 2002 **Group Art Unit** 1764 Unknown **Examiner Name** Attorney Docket No: 01360.034US1

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INFORMATION Sheet

INFORMATION DISCLOSURE IN AN APPLICATION

(Use several sheets if necessary)

OF

Docket Number 109845.178US1 Application Number 10/047,461

Applicant
Guttman et al.

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